



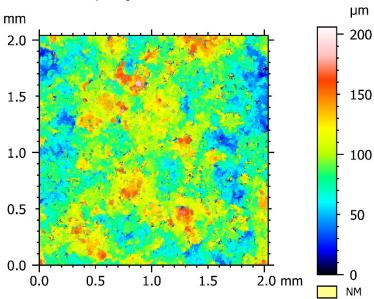
Jim Yampolsky Key Account Manager/Materials Specialist May 9, 2019





Abstract: The strength of a bond between a coating and the substrate is significantly affected by factors such as roughness and cleanliness. The ability to non-destructively characterize a surface and understand its topography and roughness is a powerful tool for understanding many aspects of surface behavior; including Corrosion.

Thermal sprayed Aluminum

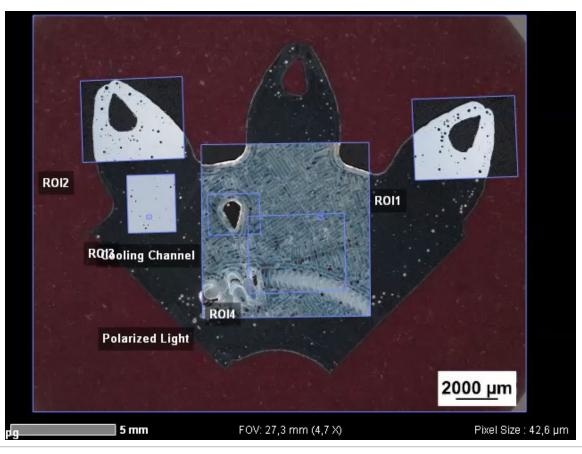


ISO 25178			
Height Parameters			
Sq	0.658	μm	
Ssk	-0.091		
Sku	10.247		
Sp	7.664	μm	
Sv	10.288	μm	
Sz	17.952	μm	
Sa	0.362	μm	
Spatial Parameters			
Sal	0.108	μm	

100	4287		
Amp	litude p	aran	neters - Roughness profile
Rp	2.65	μm	Gaussian filter, 0.25 mm
Rv	3.06	μm	Gaussian filter, 0.25 mm
Rz	5.71	μm	Gaussian filter, 0.25 mm
Rc	1.50	μm	Gaussian filter, 0.25 mm, ISO 4287 w/o amendmen.
Rt	5.71	μm	Gaussian filter, 0.25 mm
Ra	0.273	μm	Gaussian filter, 0.25 mm
кq	0.461	μm	Gaussian filter, 0.25 mm
Rsk	-0.24		Gaussian filter, 0.25 mm
Rku	9.80		Gaussian filter, 0.25 mm
Mate	Material ratio parameters - Roughness profile		
Rmr	0.445	%	c = 1 µm under the highest peak, Gaussian filter, 0
Rdc	0.450	um	p = 20%, q = 80%, Gaussian filter, 0.25 mm

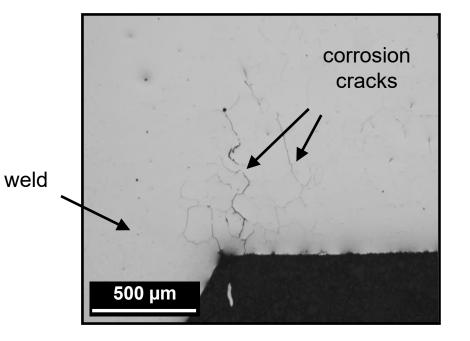


Goal: To look at multi-modal microscopy techniques as tools capable of providing a vast array of analytical data in a non-destructive manner, and show how this can be accomplished in integrated and connected solutions using both hardware and software.

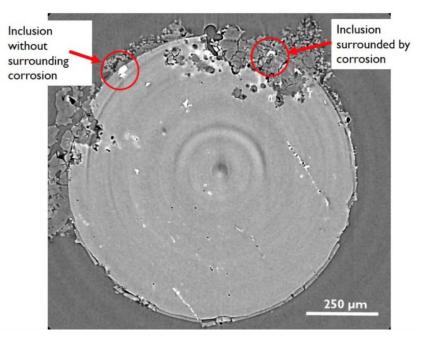


What does Corrosion look like?

Emphasis will be on highlighting work that has been done using advanced Light and Confocal, Scanning Electron, and X-Ray Microscopy solutions for surface analysis.



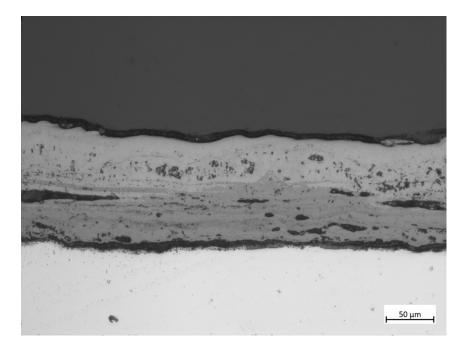
SEM – Chromium Nickel Steel

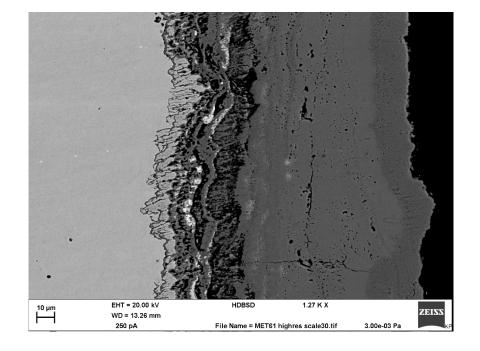


XRM – Aluminum 7475 alloy



What does Corrosion look like?



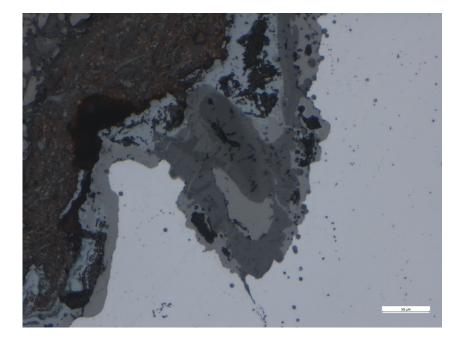


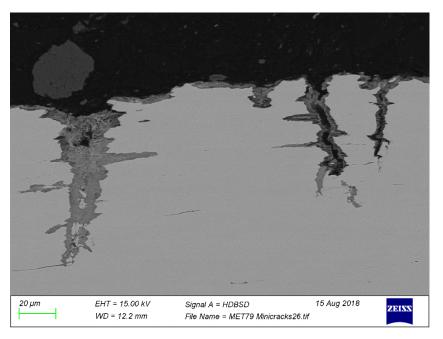
LM – Chromium Steel

SEM – Chromium Steel



What does Corrosion look like?



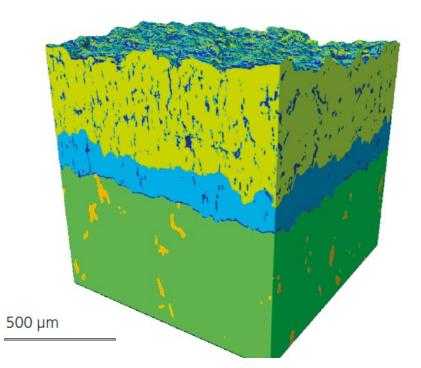


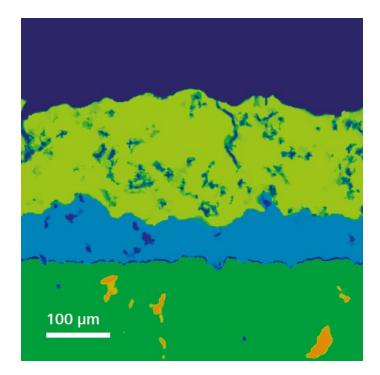
SEM – Corroded Steel

SEM – Cracks in Carbon Steel



What does Corrosion look like?



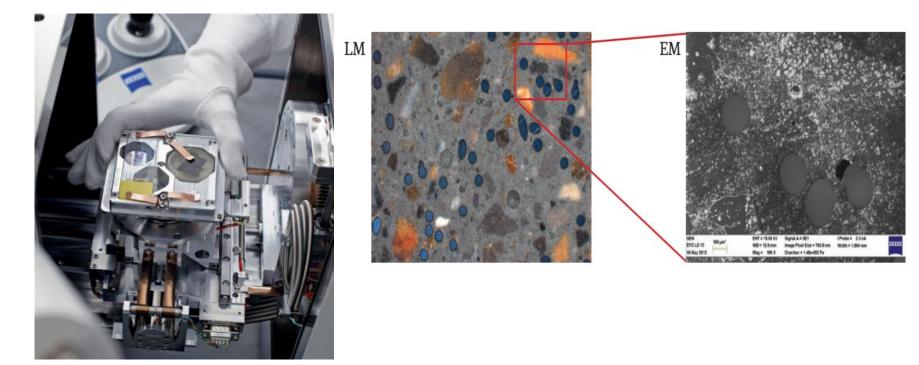


XRM – Thermal Barrier Coating (Nickel alloy base, Aluminum oxide bond coat, yttria-stabilized zirconia (YSZ) top coat



How do I get images like these?

A coordinated workflow is shown as essential in complex multiscale experiments using Light, Electron, and X-ray microscopy solutions.



Overview of Solutions



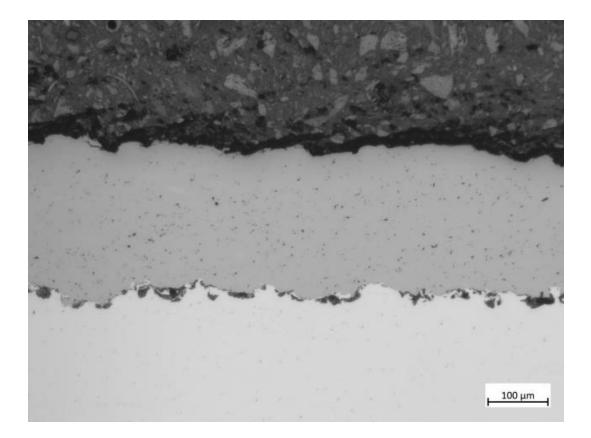
LM – Light Microscopy

- CM Confocal Microscopy
- EM Electron Microscopy (aka Scanning Electron Microscopy)
- XRM X-ray Microscopy/MicroCT



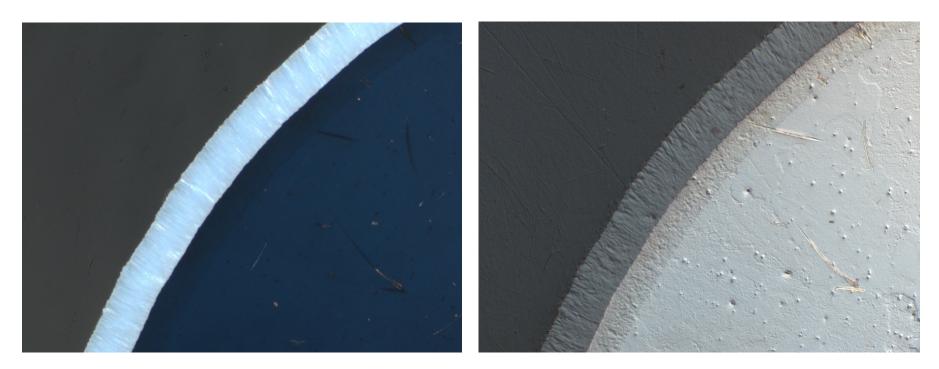
Tantalum coating on Stainless Steel Light Microscopy





Thermal Spray Coating Light Microscopy using Polarized and C-DIC techniques



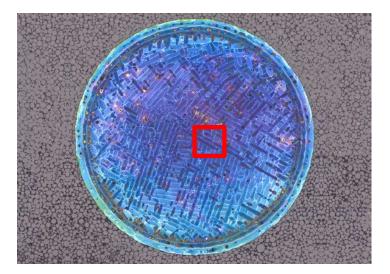


LM - Polarized light

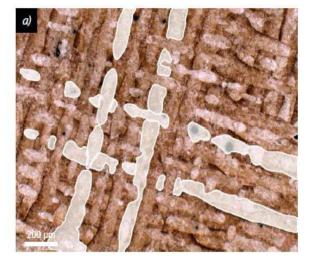
LM – Circular Differential Interference Contrast

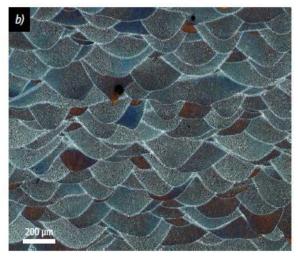
Laser sintered Powdered Metal Light Microscopy





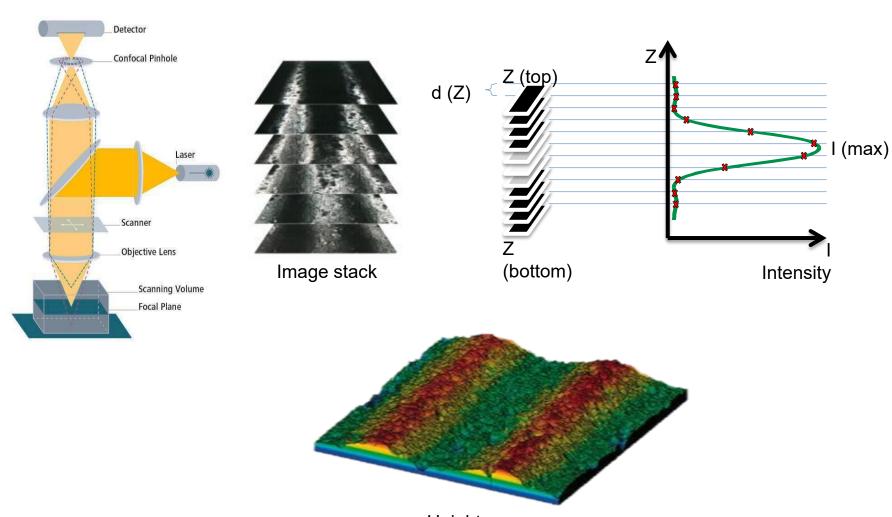
LM – Cross-section Polarized light





Confocal Microscopy Overview of Laser Scanning Microscope



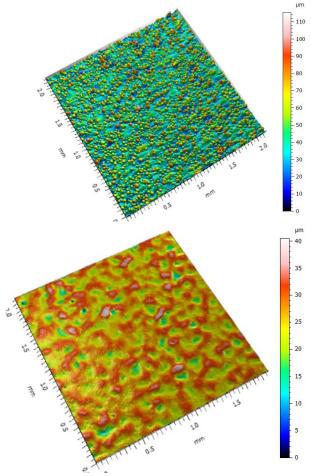


Height map

Initial Surface Roughness Evaluation of Ti-6AI-4V Grit Blasting



Confocal microscopy shows level of roughness



ISO 25178			
Height Parameters			
15.1	μm		
0.689			
3.15			
70.3	μm		
45.1	μm		
115	μm		
12.2	μm		
	Parameters 15.1 0.689 3.15 70.3 45.1 115		

25	Δftor	Crit	hlaet	ina
	After	GIII	plasi	.ing

As built

5178			
Height Parameters			
3.87	μm		
-0.228			
3.30			
14.2	μm		
26.3	μm		
40.5	μm		
3.07	μm		
	Parameters 3.87 -0.228 3.30 14.2 26.3 40.5		

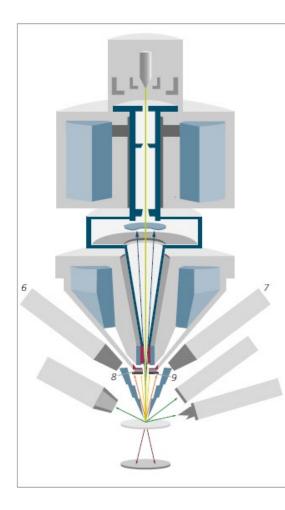
Electron Microscopy Scanning Electron Microscope (SEM)

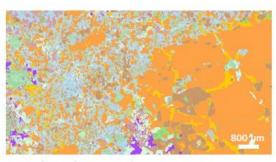


- 1) SEM is an essential tool for identifying, locating and characterizing corroded regions, elemental depletion, and corrosion products.
- 2) Particularly for parts that are exposed to high temperature or unusual chemical environments in the course of their normal performance.
- 3) Assessment of cross sections by SEM allows a whole new mode of imaging: grain boundaries which are not easily visible under the light microscope may show under SEM, with corroded/depleted layers likely revealed as well.
- 4) Routine assessment of surfaces of welds, brazes, joints, and coatings is also made stronger by SEM particularly because EDS (Energy Dispersive X-ray Spectroscopy) gives information about elemental dilution and any unusual variations in composition.

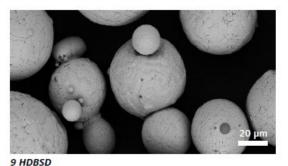
Scanning Electron Microscopy Overview



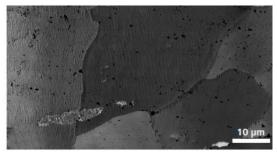




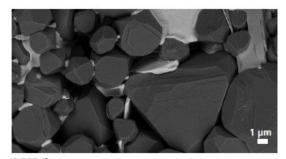
6 / 7 Advanced EDS Detection Advanced EDS analysis geometry of 8.5 mm working distance and 35° take-off angle for delivering data at twice the speed or half the probe current, Sample: courtesy of University of Leicester.



High definition BSE detector for excellent low kV compositional imaging of all samples in all vacuum modes.



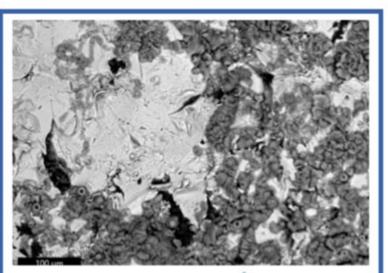
8 AsB Detector Angular selective BSE detector for crystallographic and channeling contrast imaging of metals and minerals.



9 BSD4" Four parallel outputs of the BSE detector for real-time 3D imaging and surface metrology. Example of a compositional

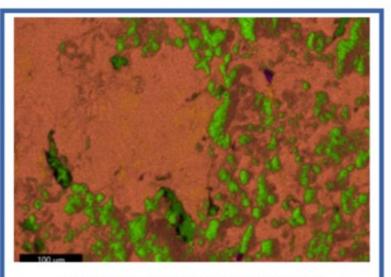
Corroded Mild Steel Electron Microscopy using BSE and EDS





Backscattered electron image of corroded mild steel, revealing backscattered electron densities that point to compositional heterogeneities as a result of corrosion

EM – BSE (Back Scattered Electron) image

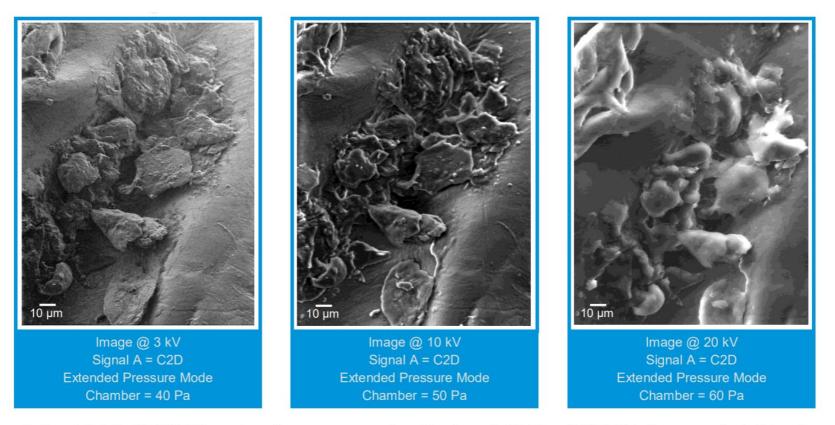


Iron (red) and Oxygen (green) elemental map confirming the location of oxidized regions on the sample

EM – EDS/EDX (Energy Dispersive X-ray Spectroscopy) image

Organic Coating Corrosion Electron Microscopy using Variable Pressure and Voltage





Surface detail of a GORE-TEX organic coating on a copper guitar string, imaged at 5, 10 and 20 kV. Note the progressive "edginess" of surface detail at lower primary beam acceleration voltages — the sweet spot for LaB₆ operation.

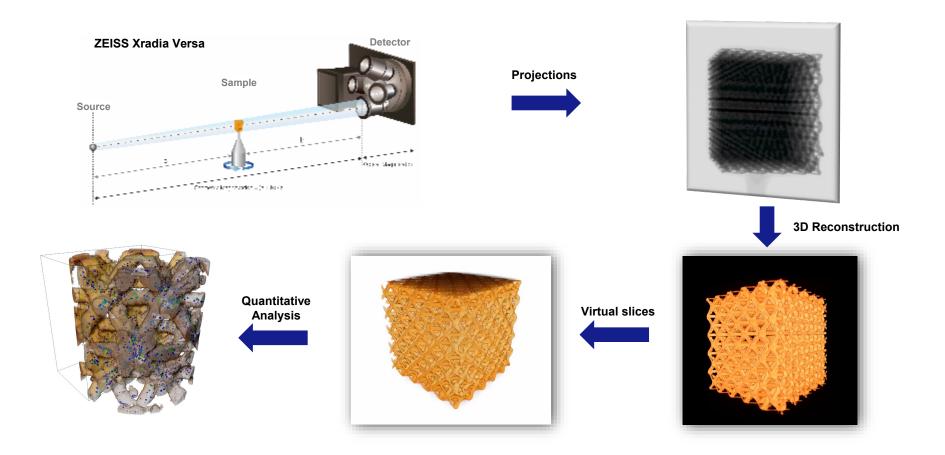
X-ray Microscopy



- X-ray microscopy (XRM), a nondestructive 3D imaging technique, is used to understand the time-dependent evolution and overall extent of corrosion damage in the surface and sub-surface regions.
- 2) Probing the internal structure without the need for complex sample preparation and physical sectioning techniques
- Moving from sub-micron XRM to nanoscale XRM, finally to FIB (Focused Ion Beam) -SEM
- 4) Utilizes 3D imaging techniques in a coordinated Correlative workflow (via hardware and software) at the micro and nanoscale to investigate corrosion damage

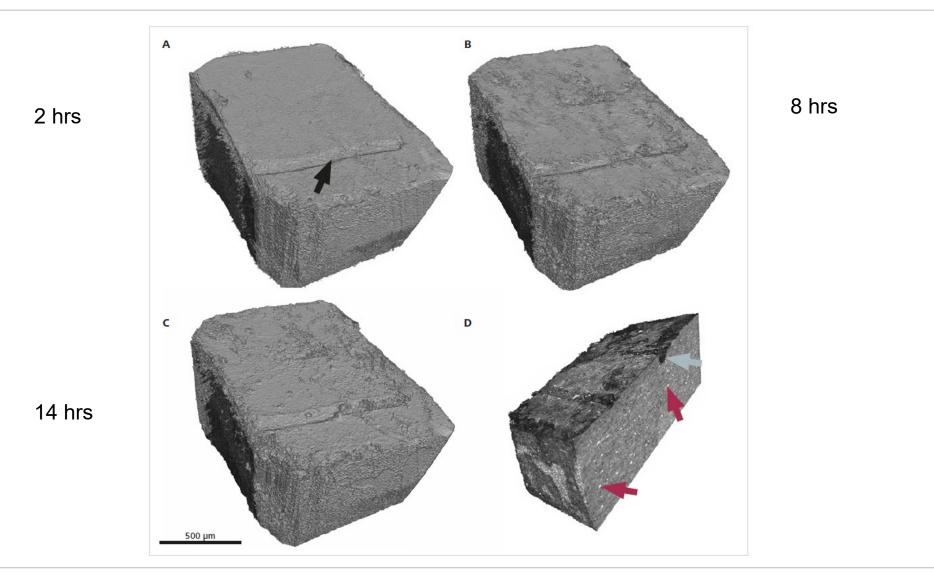
Tomography in 3D X-ray Microscopy How it works – Inconel 3D Printed lattice





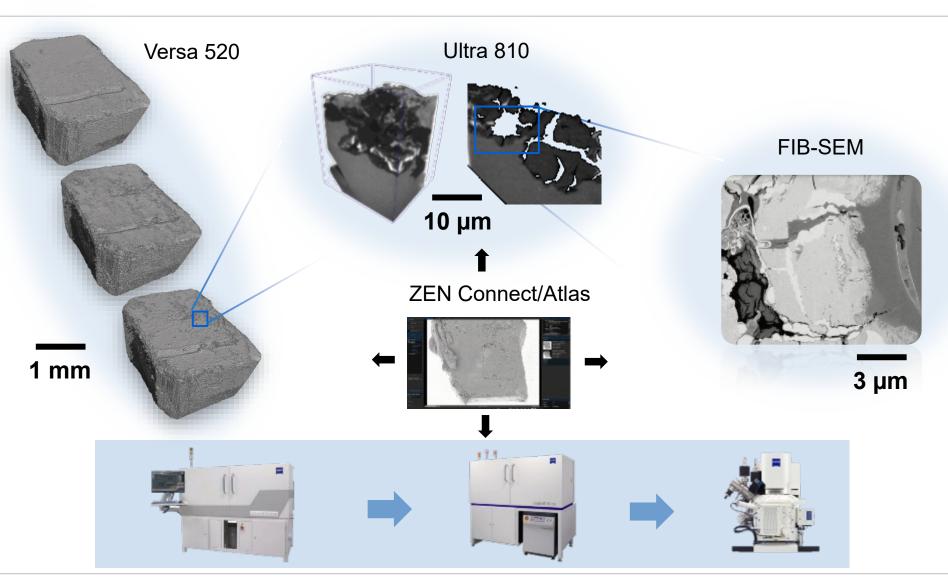
Multiscale Corrosion Damage in Magnesium Alloy In situ - Correlative Workflow using XRM and EM





Multiscale Corrosion Damage in Magnesium Alloy Correlative Workflow using XRM and EM

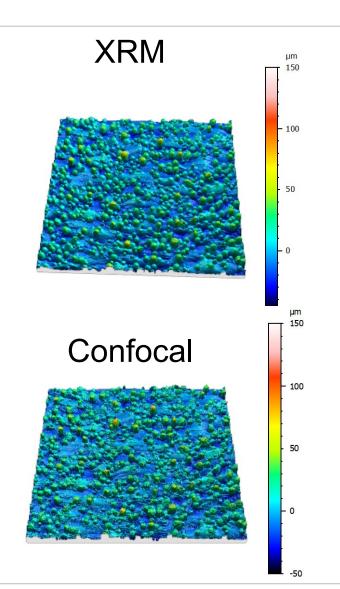




Surface Roughness Evaluation

XRM vs Confocal – Sa Comparison





Sa results between XRM and Confocal are very favorable

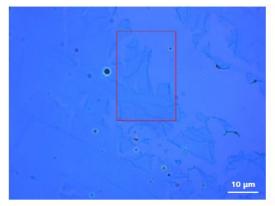
ISO 25178

Heig	ht Paramete	rs		
	520 Versa	LSM 800		
Sq	15.1	14.8	μm	
Ssk	0.700	0.776		
Sku	3.11	3.29	μm	
Sp	66.9	71.3	μm	
Sv	40.7	86.9	μm	
Sz	108	158	μm	
Sa	12.2	12.0	μm	

Graphene and Green Arsenic Correlative Microscopy from LM to EM to RAMAN



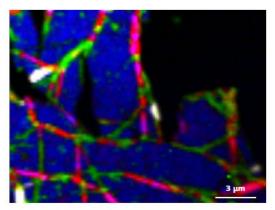
Chemical Vapor Deposition (CVD) Graphene



Light Microscope, transmitted light

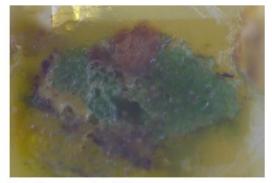


Scanning Electron Microscope, Inlens detector

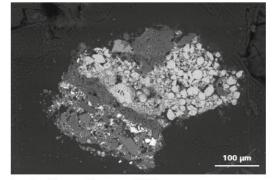


Light Microscope, Raman image

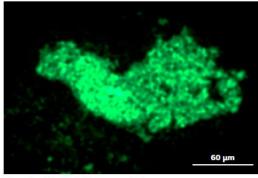
Green Arsenic Particle



Light Microscope, reflected light



Scanning Electron Microscope, BSD detector



Scanning Electron Microscope, EDX

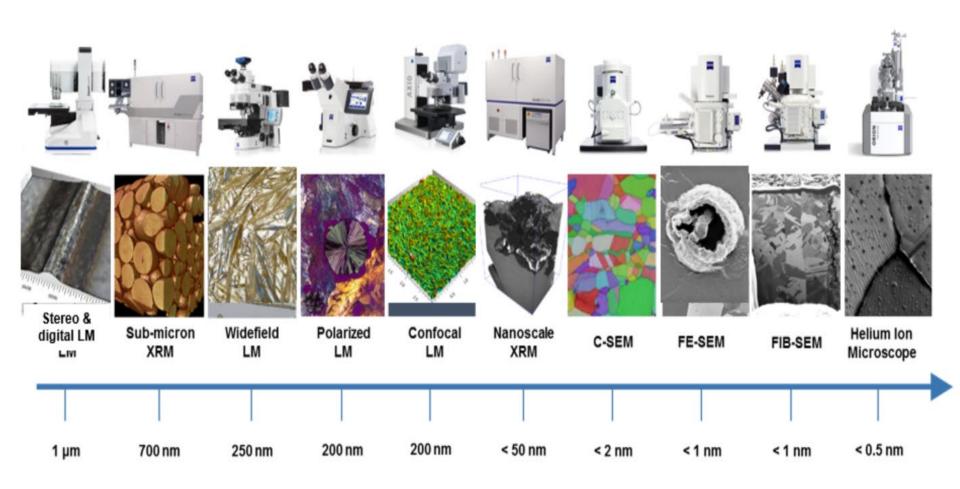


Summary

- Combining data results from multiple solutions can identify complex crack and corrosion geometries which can lead to a more complete understanding of the underlying mechanisms for Corrosion.
- Techniques exist to create a Correlative Workflow that can simplify the acquisition of data across multiple scales from Nano to Micro to Millimeter.
- The use of a semi-automated Correlative Workflow speeds up the process of searching the same ROI across multiple instruments allowing us to quickly identify areas of potential failure.
- Software and Hardware options can be combined to create a single project combining all of the data collected via Light, Confocal, Electron, and X-ray Microscopy.

Zeiss Product Solutions





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